

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/667,776	SU ET AL.	
Examiner	Art Unit	
Young J. Kim	1637	

	SEARCHED					
Class	Subclass	Date	Examiner			
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclsoed text-search strategy	11/1/2005	YJK
Inventor Name search: Xing Su; Selena Chan; Tae-Woong Koo; Mineo Yamakawa; and Andrew Berlin	11/1/2005	YJK
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